

Toluene
CMOS



Material No.: 9466-03

Batch No.: 24K1361054

Manufactured Date: 2024-11-12

Retest Date: 2029-11-11

Revision No.: 0

Certificate of Analysis

Test	Specification	Result
Assay ($C_6H_5CH_3$) (by GC)	$\geq 99.5 \%$	99.9 %
Color (APHA)	≤ 10	<5
Acidity ($\mu\text{eq/g}$)	≤ 0.2	0.1
Residue after Evaporation	$\leq 2.0 \text{ ppm}$	<1.0 ppm
Water (by KF, coulometric)	$\leq 0.03 \%$	0.01 %
Substances Darkened by H_2SO_4	Passes Test	Passes Test
Sulfur Compounds (as S)	$\leq 0.003 \%$	<0.003 %
Chloride (Cl)	$\leq 2 \text{ ppm}$	<2 ppm
Phosphate (PO_4)	$\leq 0.5 \text{ ppm}$	<0.5 ppm
Trace Impurities – Aluminum (Al)	$\leq 20 \text{ ppb}$	<5 ppb
Arsenic & Antimony (as As)	$\leq 10.0 \text{ ppb}$	<10.0 ppb
Trace Impurities – Barium (Ba)	$\leq 10.0 \text{ ppb}$	<1.0 ppb
Trace Impurities – Boron (B)	$\leq 20.0 \text{ ppb}$	<5.0 ppb
Trace Impurities – Cadmium (Cd)	$\leq 20.0 \text{ ppb}$	<1.0 ppb
Trace Impurities – Calcium (Ca)	$\leq 100.0 \text{ ppb}$	3.8 ppb
Trace Impurities – Chromium (Cr)	$\leq 10.0 \text{ ppb}$	<1.0 ppb
Trace Impurities – Cobalt (Co)	$\leq 20 \text{ ppb}$	<1 ppb
Trace Impurities – Copper (Cu)	$\leq 20.0 \text{ ppb}$	<1.0 ppb
Trace Impurities – Gallium (Ga)	$\leq 50 \text{ ppb}$	<1 ppb
Trace Impurities – Germanium (Ge)	$\leq 50.0 \text{ ppb}$	<10.0 ppb
Trace Impurities – Gold (Au)	$\leq 20 \text{ ppb}$	<5 ppb
Heavy Metals (as Pb)	$\leq 500.0 \text{ ppb}$	<500.0 ppb
Trace Impurities – Iron (Fe)	$\leq 20.0 \text{ ppb}$	<1.0 ppb
Trace Impurities – Lithium (Li)	$\leq 20.0 \text{ ppb}$	<1.0 ppb
Trace Impurities – Magnesium (Mg)	$\leq 10.0 \text{ ppb}$	<1.0 ppb
Trace Impurities – Manganese (Mn)	$\leq 10.0 \text{ ppb}$	<1.0 ppb
Trace Impurities – Nickel (Ni)	$\leq 20.0 \text{ ppb}$	<5.0 ppb
Trace Impurities – Potassium (K)	$\leq 50 \text{ ppb}$	<10 ppb

For questions on this Certificate of Analysis please contact Technical Services at 855.282.6867 or +1.610.386.1700

Avantor Performance Materials, LLC

100 Matsonford Rd, Suite 200, Radnor, PA, 19087, U.S.A. Phone 610.386.1700

Toluene
CMOS



Material No.: 9466-03
Batch No.: 24K1361054

Test	Specification	Result
Trace Impurities – Silicon (Si)	<= 100.0 ppb	<10.0 ppb
Trace Impurities – Silver (Ag)	<= 20.0 ppb	<1.0 ppb
Trace Impurities – Sodium (Na)	<= 100.0 ppb	<5.0 ppb
Trace Impurities – Strontium (Sr)	<= 10.0 ppb	<1.0 ppb
Trace Impurities – Tin (Sn)	<= 30.0 ppb	<10.0 ppb
Trace Impurities – Zinc (Zn)	<= 20.0 ppb	<1.0 ppb
Particle Count – 1.0 µm and greater	<= 10 par/ml	2 par/ml

For Microelectronic Use

Country of Origin: United States
Packaging Site: Paris Mfg Ctr & DC


Michelle Bales
Sr. Manager, Quality Assurance

For questions on this Certificate of Analysis please contact Technical Services at 855.282.6867 or +1.610.386.1700

Avantor Performance Materials, LLC

100 Matsonford Rd, Suite 200, Radnor, PA, 19087, U.S.A. Phone 610.386.1700